

attachment to PTOL - 413
(do NOT detach)

NAKANO et al., SN 10/075,244
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IN THE CLAIMS:

Proposal - 6/12/06

1. (Currently Amended) A method for processing a specimen using a plasma, comprising:

generating a plasma in a processing chamber in which the specimen is disposed; and

5 processing the specimen with the plasma generated in the processing chamber, wherein

the processing of the specimen comprises:

an irradiation operation for projecting and scanning a light beam into the processing chamber through an observation window of the processing chamber;

10 a detection operation for detecting a light of the projected light beam which is

reflected from an inside wall of the processing chamber, the light being detected by

~~WALL REFLECTED~~ separating a light component from light emanated from the plasma ~~and~~ and light reflected

from the inside wall by use of a spectroscope; and

a signal processing operation for obtaining information on a state of

15 contamination of the inside wall of the processing chamber, by processing a signal

obtained at the detection operation by referring to a database storing predetermined

relationships between a signal ~~signals~~ obtained from said detection of light from said

inside wall and a state ~~states~~ of contamination of said inside wall.]

TO DERIVE A STATE OF CONTAMINATION
CORRESPONDING TO THE WALL-REFLECTED LIGHT
SIGNAL, FROM THE ELECTRONIC DATABASE.

2. (Previously Presented) A method for processing a specimen using a plasma according to Claim 1, comprising